



Reliability Analysis of Electrotechnical Devices

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Message from the Guest Editor

Dear Colleagues,

The smart world involves complex electrotechnical systems and devices, which have improved our lives significantly. Consequently, we are heavily dependent on them, and their reliability has become crucial. However, ensuring the reliability of complex systems and devices can be challenging, especially in a cost-effective manner. This Special Issue focusses on various methods and examples to improve, evaluate, and predict the reliability of electrotechnical systems and devices that constitute smart systems and the smart world.

Topics of interest to be covered by the Special Issue include but are not limited to reliability and its related topics of the following electrotechnical systems and devices:

- Electron devices;
- Electro-optical devices;
- Batteries and packs;
- MEMS and NEMS;
- Vacuum devices;
- Renewable energy devices and systems;
- Bio-medical electronic devices;
- Wearable devices and systems;
- Others





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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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